US00D360598S

United States Patent [19]

Wada et al.

[11] **Patent Number: Des. 360,598**

[45] **Date of Patent: ** Jul. 25, 1995**

[54] **CONSOLE FOR MEASUREMENT SCANNER FOR SEMI-CONDUCTOR**

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[73] Assignee: **Hitachi, Ltd.**, Tokyo, Japan

[**] Term: **14 Years**

[21] Appl. No.: **25,208**

[22] Filed: **Jul. 26, 1994**

[30] **Foreign Application Priority Data**

Apr. 15, 1994 [JP] Japan 6-10334

[52] **U.S. Cl.** **D10/75**

[58] **Field of Search** .... D10/46, 75; D13/123, D13/162, 163; D14/102, 107; D24/186; 348/135, 91, 94, 95, 130, 92, 142, 93, 162, 161, 125; 356/380, 386, 121, 237, 387; 360/9.1, 72.1; 382/34; 250/223 B

[56] **References Cited**

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[57] **CLAIM**

The ornamental design for a console for measurement scanner for semi-conductor, as shown.

DESCRIPTION

FIG. **1** is a front, top and right side perspective view of a console for measurement scanner for semi-conductor showing our new design;

FIG. **2** is a front elevational view thereof;

FIG. **3** is a right side view thereof;

FIG. **4** is a rear elevational view thereof;

FIG. **5** is a left side view thereof;

FIG. **6** is a top plan view thereof; and,

FIG. **7** is a bottom plan view thereof.

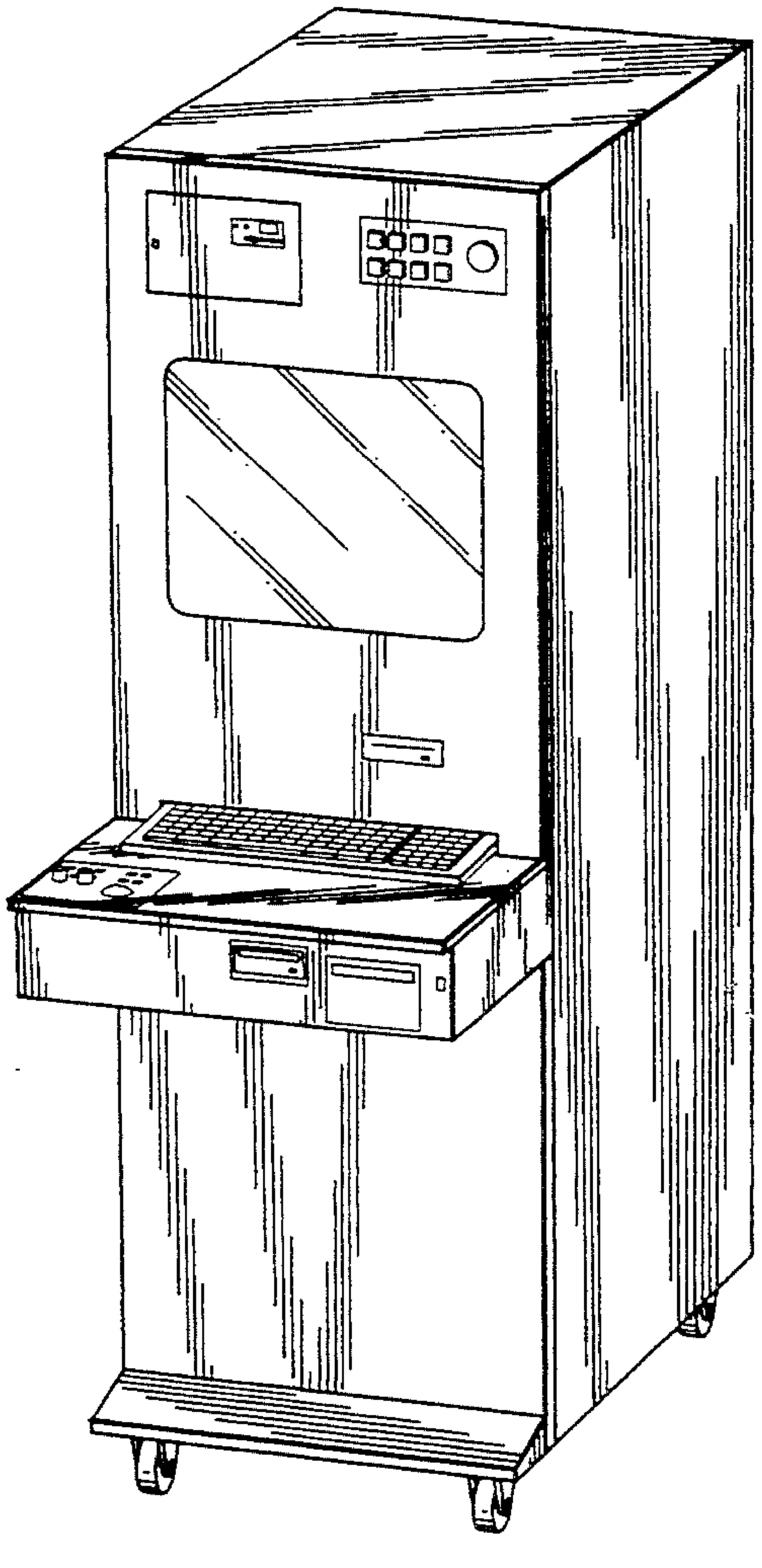

FIG. 7

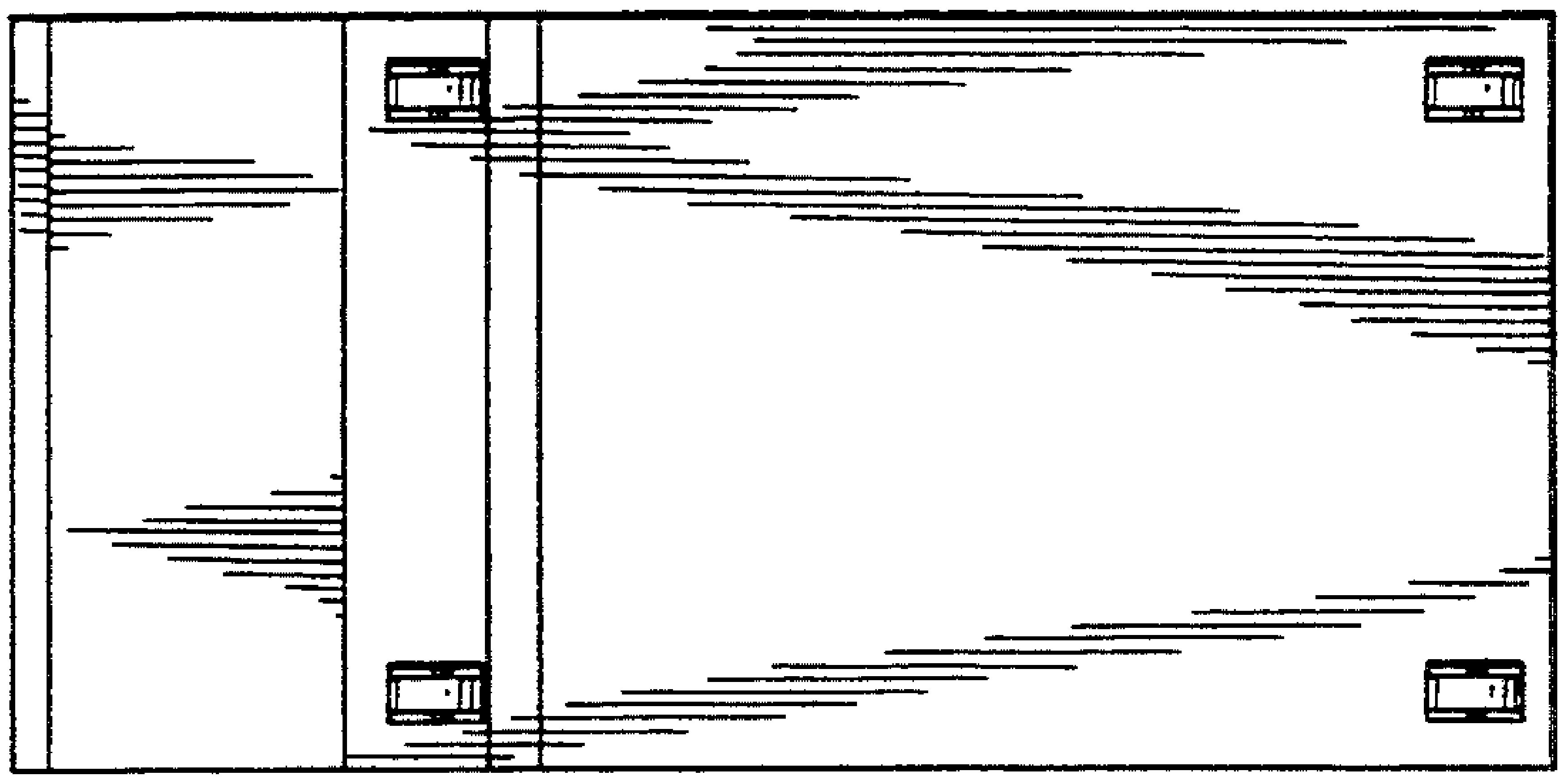

FIG. 6

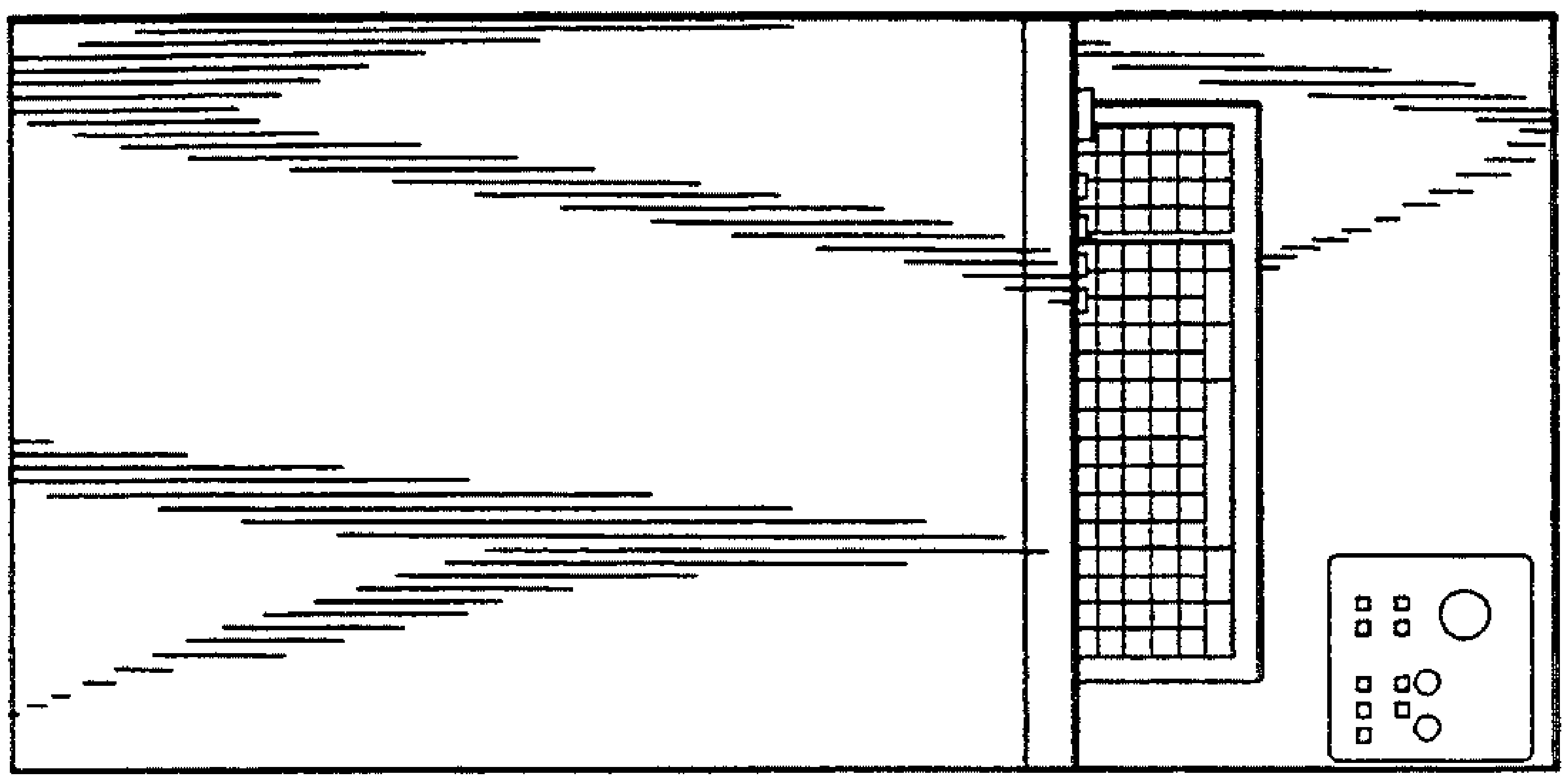

FIG. 5